

<b>Notice of References Cited</b>	Application/Control No. 10/581,980		Applicant(s)/Patent Under Reexamination NAGASHIMA ET AL.	
	Examiner /Elizabeth A. Bolden/		Art Unit 1793	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,362,689	11-1994	Morimoto et al.	501/70
*	B	US-2003/0083188	05-2003	Seto et al.	501/71
*	C	US-6,753,280	06-2004	Seto et al.	501/70
*	D	US-5,077,133	12-1991	Cheng, J. Joseph	428/426
*	E	US-5,723,390	03-1998	Kijima et al.	501/70
*	F	US-2002/0198094	12-2002	Arbab et al.	501/64
*	G	US-2004/0067836	04-2004	Boulos et al.	501/070
*	H	US-2004/0142811	07-2004	Torr et al.	501/070
*	I	US-5,240,886	08-1993	Gulotta et al.	501/70
*	J	US-5,214,008	05-1993	Beckwith et al.	501/69
*	K	US-5,830,568	11-1998	Kondo, Takeshi	428/328
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 03187946 A	08-1991	Japan	CHENG, J JOSEPH	
*	O	WO 9707356 A1	02-1997	World Intellect	FROEHLICH, MANFRED	
*	P	JP 04231347 A	08-1992	Japan	GULOTTA et al.	
*	Q	JP 06166536 A	06-1994	Japan	BECKWITH et al.	
*	R	JP 10297934 A	11-1998	Japan	MORIMOTO et al.	
*	S	JP 09208254 A	08-1997	Japan	MORIMOTO et al.	
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.